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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/734,905		12/12/2003	Yean-Yow Hwang	15114-067400US	2440	
26059	7590	12/02/2005		EXAM	EXAMINER	
		TOWNSEND AND	LIN, SUN J			
8TH FLOOR		RO CENTER		ART UNIT PAPER NUMBER		
SAN FRAN	CISCO, (	CA 94111-3834		2825		

DATE MAILED: 12/02/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

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· · · · · · · · · · · · · · · · · · ·	Application No.	Applicant(s)	
	10/734,905	HWANG ET AL.	
Office Action Summary	Examiner	Art Unit	
	Sun J. Lin	2825	
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet wi	th the correspondence address -	-
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D.  - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNIO (36(a). In no event, however, may a rewill apply and will expire SIX (6) MON e, cause the application to become AB	CATION.  eply be timely filed  THS from the mailing date of this communical  ANDONED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed on 30 S	September 2005.		
2a) ☐ This action is <b>FINAL</b> . 2b) ☑ This	s action is non-final.		
3) Since this application is in condition for allowa	nce except for formal matt	ers, prosecution as to the merits	is
closed in accordance with the practice under E	Ex parte Quayle, 1935 C.D	. 11, 453 O.G. 213.	
Disposition of Claims			
4) Claim(s) 1-4 and 6-15 is/are pending in the ap	plication.		
4a) Of the above claim(s) is/are withdra			
5) Claim(s) is/are allowed.			
6)⊠ Claim(s) <u>1-4 and 6-15</u> is/are rejected.			
7) Claim(s) is/are objected to.			
8) Claim(s) are subject to restriction and/o	or election requirement.		
Application Papers			
9) The specification is objected to by the Examine	er.		
10)⊠ The drawing(s) filed on <u>12 December 2005 and</u>	<u>d 14 September 2005</u> is/ar	e: a)⊠ accepted or b)⊡ object	ted to by
the Examiner.			
Applicant may not request that any objection to the	drawing(s) be held in abeyar	ce. See 37 CFR 1.85(a).	
Replacement drawing sheet(s) including the correct	·	· · · -	
11)☐ The oath or declaration is objected to by the Ex	xaminer. Note the attached	Office Action or form PTO-152	•
Priority under 35 U.S.C. § 119			
<ul> <li>12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority document</li> <li>2. Certified copies of the priority document</li> <li>3. Copies of the certified copies of the priority application from the International Bureau</li> <li>* See the attached detailed Office action for a list</li> </ul>	ts have been received. ts have been received in A rity documents have been u (PCT Rule 17.2(a)).	pplication No received in this National Stage	
Attachment(e)			
Attachment(s)  1) Notice of References Cited (PTO-892)	4) Interview S	iummary (PTO-413)	
2) Notice of References Cited (PTO-692)  Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s	)/Mail Date	
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)	5) Notice of Ir	formal Patent Application (PTO-152)	

Paper No(s)/Mail Date \_\_\_\_

6) Other: \_\_\_\_\_.

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#### **DETAILED ACTION**

1. This office action is in response to Amendments & Remarks filed on 09/30/2005 regarding to application 10/734,905 filed on 12/12/2003. Claim 5 has been cancelled without prejudice. Claims 1-4 and 6-15 remain pending in the application.

## Claim Objections

Claim listed below is objected to because of the following informalities:
 Claim 13, line 7, after "wherein" insert —the netlist performed by—.

Appropriate correction is required.

#### Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- (1). Determining the scope and contents of the prior art.
- (2). Ascertaining the differences between the prior art and the claims at issue.
- (3). Resolving the level of ordinary skill in the pertinent art.
- (4). Considering objective evidence present in the application indicating obviousness or nonobviousness.
- 4. Claims 1 4, 6, 7 and 13 15 are rejected under 35 U.S.C. 103(a) as being unpatentable over U.S. Patent No. 5,594,657 to <u>Cantone et al.</u> over IEEE Paper entitled "On Area/Depth" Trade-Off in LUT-Based FPGA Technology Mapping" authored by Cong & Ding in view of U.S. Patent No. 6,088,262 to Nasu.

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5. As to Claim 1, <u>Cantone et al.</u> show and teach the following subject matter:

- <u>Computer aided design</u> (CAD) system for implementation of FPGA [col. 1, line 11 18; Fig. 1];
- User <u>entering</u> (i.e., <u>providing</u>) CAD system a <u>High-level application netlist language</u> (i.e., <u>high-level design language</u>) <u>description of a (logic) circuit</u> [col. 3, line 15 25]; High level circuit description [abstract]; specifying a <u>Boolean function</u> (i.e., <u>logic function</u>) using <u>Boolean equation</u> (i.e., <u>high-level design language</u>) [col. 14, line 20 25]; logical gate [col. 14, line 38]; Notice that (1) a <u>logic circuit</u> can be described by a <u>logic function</u> (<u>Boolean function</u>) using a <u>Boolean equation</u> (<u>high-level design language</u>) (2) the <u>logic function</u> can be synthesized using <u>logic gates</u> including AND, OR, INV, NAND, NOR etc.

<u>Cantone et al.</u> do not teach (1) synthesizing logic gates to respectively obtain a <u>first alternative netlist</u> and a <u>second alternative netlist</u> for the <u>logic function</u>, (2) performing a <u>technology mapping</u> of the <u>first alternative netlist</u> to obtain a <u>first mapping netlist</u> and performing a <u>technology mapping</u> of the <u>second alternative netlist</u> to obtain a <u>second mapping netlist</u> (3) selecting one of the corresponding <u>first mapping netlist</u> or <u>second mapping netlist</u> based on <u>design criteria</u>. But <u>Cong & Ding</u> teach <u>depth-optimal mapping</u> and <u>area-minimizing mapping</u> of a Boolean circuit using <u>lookup-table (LUT)</u> <u>based FPGA technology mapping</u> – [title; abstract].

### Cong & Ding show and teach the following subject matter:

- Synthesizing <u>logic gates</u> (i.e., NAND and NOR) to obtain a <u>first alternative</u>
   <u>netlist</u> for a <u>logic circuit</u>, which can be expressed by a <u>logic function</u> [Fig. 2(a)]; Notice that the <u>depth</u> of the <u>first alternative netlist</u> is 7;
- Performing <u>depth-optimal technology mapping</u> of the <u>first alternative netlist</u> to obtain a <u>depth-optimal mapping solution</u> (i.e., <u>first mapping netlist</u>) of depth 2, using 6 LUT's [Fig. 2(b)];
- Synthesizing <u>logic gates</u> (i.e., NAND and NOR) to obtain a <u>second alternative</u>
   <u>netlist</u> for the same logic circuit; Notice that (1) for current study, the gate
   configuration of the <u>second alternative netlist</u> is the same as that of the <u>first</u>
   <u>alternative netlist</u> (2) the gate configurations of the <u>first alternative netlist</u> and

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the <u>second alternative netlist</u> can be different if structural gate decomposition is applied;

- Performing <u>area-optimal technology mapping</u> of the <u>second alternative netlist</u> to obtain an <u>area-optimal mapping solution</u> (i.e., <u>second mapping netlist</u>) of depth 5, using 6 LUT's [Fig. 2(b)];
- Good/optimal mapping solutions under different <u>optimization objectives</u> (i.e., <u>design criteria</u>) [page 137, right column].

Notice that selection of the <u>first mapping netlist</u> (<u>depth-optimal mapping solution</u>) or <u>area-optimal mapping solution</u> is based on <u>design criteria</u> (i.e., <u>depth-optimal objective</u>) of the logic circuit. <u>Cong &Ding</u> also teach that, using graphical representations, a set of visible mapping solutions for a given (logic) design can be obtained in order to select a mapping option to meet various area and depth requirements – [page 138, first paragraph on left column].

Therefore, it would have been obvious at the time the invention was made to a person having ordinary skill in the art to have applied the teachings of <u>Cong & Ding</u> in utilizing graphical representations to generate a set of visible mapping solutions for a given (logic) design in order to <u>select a mapping option</u> to meet various area and depth requirements thereby achieving a <u>selected mapping netlist</u>.

In addition, *Cong & Ding* also teach the following subject matter:

- First mapping netlist comprises a plurality of logic gate array block [Fig. 2(b)];
- <u>Re-mapping</u> for area minimization [page 138, left col., second paragraph];
   <u>area/depth trade off</u> in LUT-based FPGA technology mapping [title]; Notice
   that the (1) Re-mapping can also be applied for depth minimization (2) <u>re-mapping</u>, <u>area/depth trade off</u> is applied for <u>optimizing</u> the <u>selected mapping</u>
   <u>netlist</u>;
- After optimizing, performing a <u>technology mapping</u>, <u>using RAM memory to</u> <u>realize each LUT</u>, on the <u>selected mapping netlist</u> – [col. 18, line 59 – 67].

The <u>first alternative netlist</u> shown in Fig. 2(b) of <u>Cong et al.</u> comprises logic gates.

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<u>Cong & Ding</u> shows in Fig. 2(b) that the <u>first mapping netlist</u> comprises logic <u>gate</u> <u>array blocks</u>. Although <u>Cong & Ding</u> and <u>Cantone et al.</u> do not teach that the logic gate array blocks are <u>digital signal processing blocks</u>, it is well known in the art that a logic <u>gate array block</u> can be designed to perform a digital signal processing function – [See teachings disclosed by <u>Nasu</u>: col. 12, line 46 – 51]. Notice that a <u>logic gate array block</u> having digital signal processing function is a <u>digital signal processing block</u>. Therefore, a technology mapping can be applied on a plurality of <u>digital signal processing blocks</u> to obtain a first mapping netlist in processes of optimization in order to meet various area and depth requirements in design of desired <u>digital signal processing blocks</u>.

For reference purposes, the explanations given above in response to Claim 1 are called [Response A] hereinafter.

- 6. As to Claims 2 and 3, reasons are included in [Response A] given above. Notice that <u>depth-optimal mapping</u> is equivalent to <u>delay-optimal mapping</u>; optimizing delay is achieved by optimizing depth.
- 7. As to Claim 4, reasons are included in [Response A] given above. The <u>first</u> <u>mapping netlist</u> shown in Fig. 2(b) comprises LUT structures, whose logic functions are represented by a set of logic blocks made of logic gates.
- 8. As to Claim 6, reasons are included in [Response A] given above.
- 9. As to Claim 7, reasons are included in [Response A] given above.
- 10. As to Claim 13, reasons are included in [Response A] given above. Notice the following:
  - a <u>netlist</u> ⇔ a <u>first alternative netlist</u> or a <u>second alternative netlist</u>;
  - a <u>first technology mapping</u> 

     a <u>depth-optimal technology mapping</u> or a <u>area-optimal technology mapping</u> of netlist into gate array blocks, which are to be implemented using LUT's;
  - a <u>synthesis optimization</u> ⇔ <u>area/depth trade-off</u> on the netlist;

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 a <u>second technology mapping</u> ⇔ LUT realization of gate array blocks using RAM memory.

- 11. As to Claim 14, the <u>first technology mapping</u> maps the netlist to a <u>LUT-based</u> <u>FPFA</u>, which is the same target technology (LUT-based FPGA) as the <u>second</u> <u>technology mapping</u>.
- 12. As to Claim 15, reasons are included in [Response A] given above.
- 13. Claims 8 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over U.S. Patent No. 5,594,657 to <u>Cantone et al.</u> and of IEEE Paper entitled "On Area/Depth" Trade-Off in LUT-Based FPGA Technology Mapping" authored by <u>Cong & Ding</u> and U.S. Patent No. 6,088,262 to <u>Nasu</u> in view of IEEE Paper entitled "Structural Gate Decomposition for Depth-Optimal Technology Mapping in LUT-Based FPGA Designs" authored by <u>Cong & Hwang</u>.
- 14. As to Claim 8, in addition to reasons included in [Response A] given above, <u>Cantone et al.</u> and <u>Cong & Ding</u> show and teach the subject matter with the following equivalences:
  - <u>generating</u> a <u>first alternative netlist</u> for a <u>logic function</u> ⇔ <u>synthesizing</u> a <u>first alternative netlist</u> (e.g., depth-optimal LUT-based netlist) for a <u>logic function</u>;
  - generating a <u>second alternative netlist</u> for the <u>logic function</u> 
     ⇔ <u>synthesizing</u> a <u>second alternative netlist</u> (e.g., area-optimal LUT-based netlist) for the <u>logic</u> function;
  - Selecting one of the <u>first alternative netlist</u> or the <u>second alternative netlist</u> as
    a <u>selective alternative netlist</u> based on results of a <u>technology mapping</u> (i.e.,
    LUT-based technology mapping) of the <u>first alternative netlist</u> and the <u>second</u>
    alternative netlist [Response A; Cong & Ding: Fig. 2].

<u>Cantone et al.</u>, <u>Cong & Ding</u> and <u>Nasu</u> do not teach that <u>gate configuration</u> of the <u>second alternative netlist</u> is different from that of the <u>first alternative netlist</u>. But <u>Cong & Hwang</u> teach structural gate decomposition for depth-optimal technology mapping in LUT-based FPGA designs – [title; abstract]. Notice that the structural gate

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decomposition is applied to change the <u>gate structure</u> of a given logic circuit. <u>Cong & Hwang</u> also teach that <u>structural gate decomposition</u> is performed on netlist of a logic circuit in order to allow mapping algorithms to obtain the <u>smallest mapping depth</u> – [page 196, second paragraph].

Therefore, it would have been obvious at the time the invention was made to a person having ordinary skill in the art to have applied the teachings of <u>Cong & Hwang</u> in performing <u>structural gate decomposition</u> on the <u>first alternative netlist</u> of the logic circuit under study in order to allow mapping algorithms being utilized thereby achieving the <u>smallest mapping depth</u>.

Notice that, when the <u>structural gate decomposition</u> is performed on the <u>first</u> <u>alternative netlist</u>, the gate configuration of the <u>first alternative netlist</u> is different from that of the <u>second alternative netlist</u>.

For reference purposes, the explanations given above in response to Claim 8 are called [Response B] hereinafter.

15. As to Claim 9, reasons are included in [Response A] given above. As explained in [Response A], <u>depth-area trade-off</u> is performed by <u>re-mapping</u> a netlist for optimization; it is applied to perform a <u>synthesis optimization</u> on the selected alternative netlist to obtain an optimized selected alternative netlist.

For reference purposes, the explanations given above in response to Claim 9 are called [Response C] hereinafter.

- 16. As to Claim 10, reasons are included in [Response A], [Response B] and [Response C] given above. Notice that a technology mapping
- 17. As to Claims 11 and 12, reasons are included in [Response A] and [Response B] given above.

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### Response to Amendment and Remarks

18. Applicants' amendment and remarks filed on 09/30/2005 have been reviewed. Due to newly found prior art, responses cited in the Office Action mailed to the applicants on 03/11/2005 are reversed. Detailed responses are given above.

#### Conclusion

19. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sun J Lin whose telephone number is (571) 272 - 1899. The examiner can normally be reached on Monday-Friday 9:30AM - 6:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew S Smith can be reached on (571) 272 - 1907. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Sun James Lin Patent Examiner Art Unit 2825 November 29, 2005

James Burn firs



Jonathan M. Hollander, Reg. No. 48,717, (415) 576-0200 Titled: Estimating Quality During Early Synthesis App. No.: 10/734,905 Filed: December 12, 2003 Dekt. No.: 015114-067400US Replacement Sheet 1 of 7

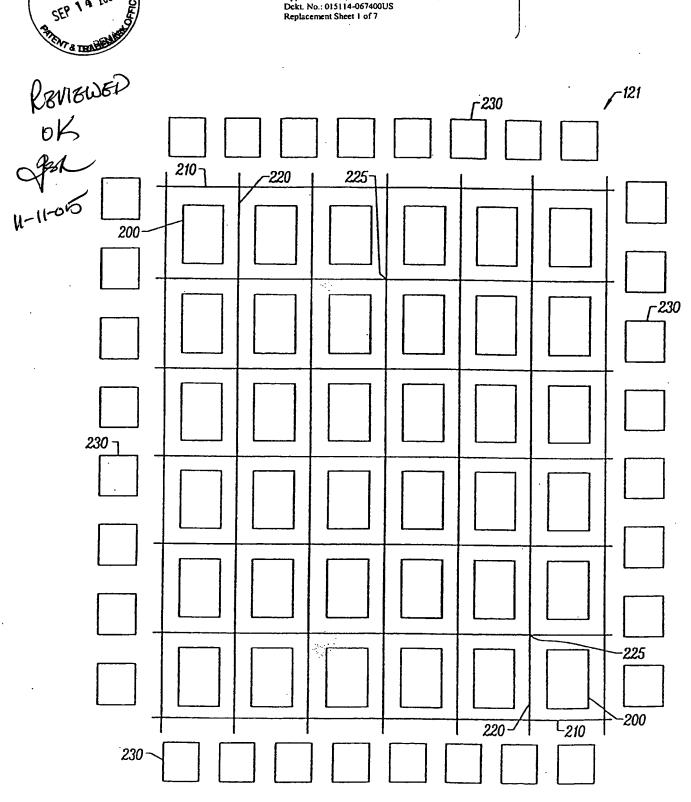
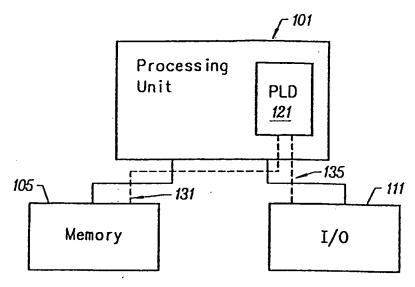


FIG. 2 (PRIOR ART)



-FIG. 1C

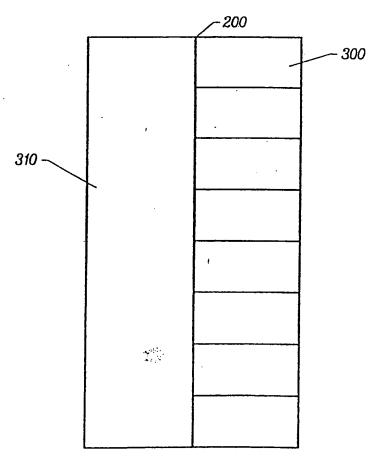
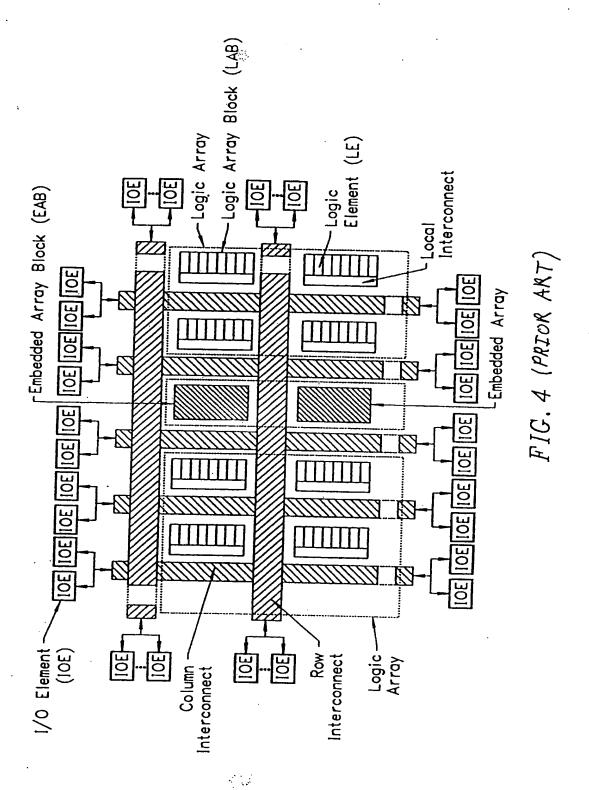


FIG. 3 (PRIOR ART)

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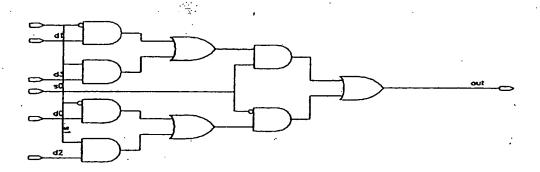


FIGURE 7 (PRIOR ART)

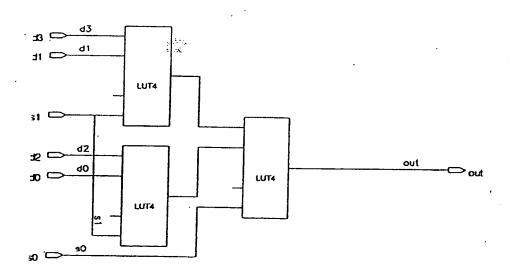


FIGURE 8

Jonathan M. Hollander, Reg. No. 48,717, (415) 576-0200 Titled: Estimating Quality During Early Synthesis App.No.: 10/734,905 Filed: December 12, 2003 Dckt. No.: 015114-067400US Replacement Sheet 5 of 7

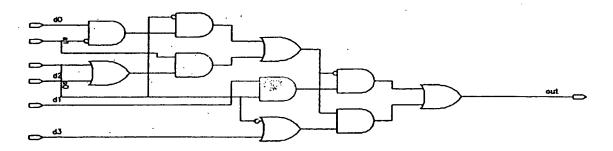


FIGURE 9 (PRIOR ART)

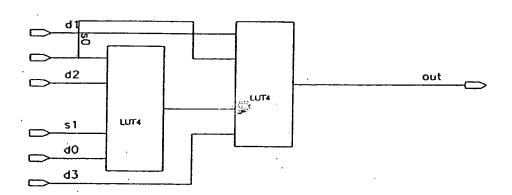
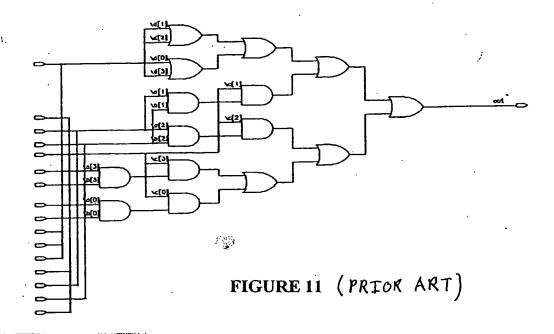
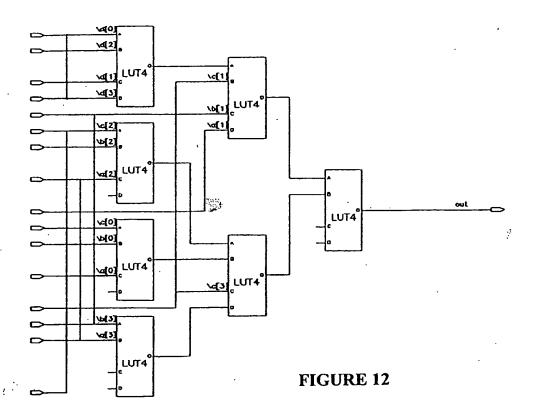


FIGURE 10

4 54.

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